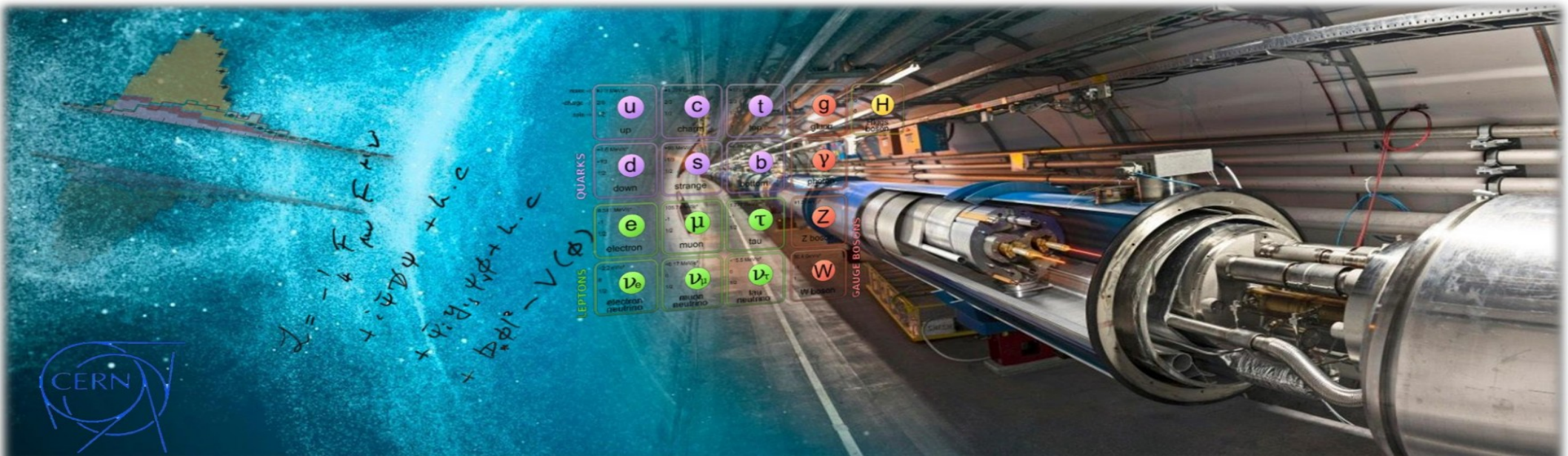
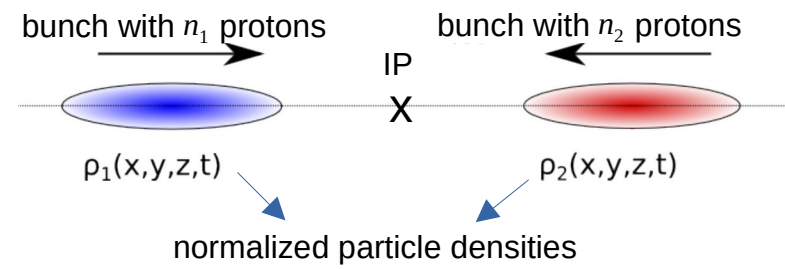


# Absolute luminosity calibration in pp collisions at 900 GeV center-of-mass energy in the ATLAS experiment

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29/08/22





Luminosity describes the capability of an accelerator to produce particle interactions.

**LUMINOSITY**  $\mathcal{L} = \frac{dN}{dt} \frac{1}{\sigma} [cm^{-2} s^{-1}]$

number of interactions per unit time (rate,  $R$ )

cross-section of a given process

- [1] arXiv: 1603.09222 [hep-ex]
- [2] arXiv: 1910.08819 [hep-ex]

Number of pp collisions per one bunch-crossing

Number of colliding bunches

Revolution frequency (11246 Hz at the LHC)

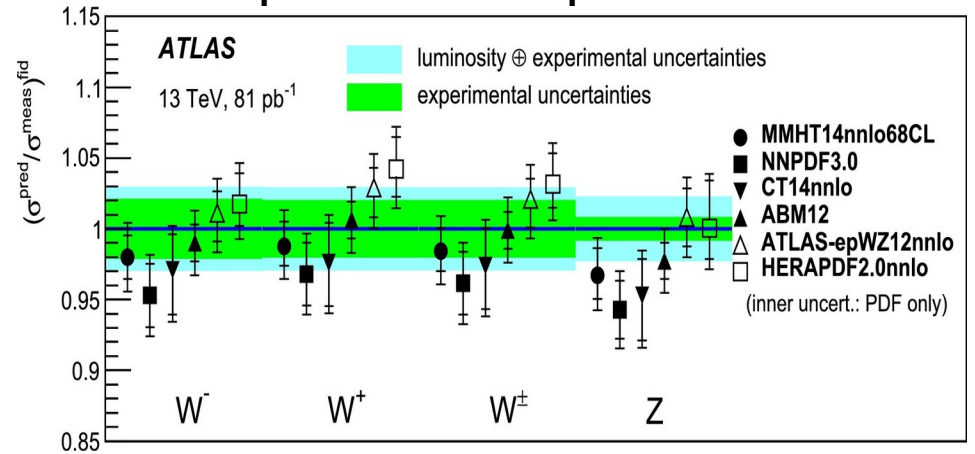
$$\mathcal{L} = \frac{R}{\sigma} = \frac{\mu n_b f_r}{\sigma_{inel}} = \frac{\epsilon \mu n_b f_r}{\epsilon \sigma_{inel}} = \frac{\mu_{eff} n_b f_r}{\sigma_{eff}}$$

Detector efficiency

Inelastic cross-section

Effective or visible quantities measured in experiment

### Impact of $\sigma_L$ on SM precision test



- [1]  $\sigma_{W^+}^{tot} = 11.83 \pm 0.02$  (stat)  $\pm 0.32$  (syst)  $\pm 0.25$  (lumi)
- [2]  $\sigma_{t\bar{t}} = 826.4 \pm 3.6$  (stat)  $\pm 11.5$  (syst)  $\pm 15.7$  (lumi)  $\pm 1.9$  (beam) pb

- Measuring  $\sigma_{tot}(pp \rightarrow X) \rightarrow$  fundamental quantity
- CAN NOT be calculated from the first principles
- CAN be measured using Optical theorem:

$$\sigma_{tot}^2 = \frac{16\pi(\hbar c)^2}{1 + \rho^2} \frac{d\sigma_{el}}{dt} \Big|_{t=0},$$

$\rho$  is small correction related to elastic scattering amplitude:  $\rho = \frac{Re[f_{el}(t)]}{Im[f_{el}(t)]} \Big|_{t \rightarrow 0}$ .

$t$  is variable related to the scattering angle used to describe elastic-scattering events.

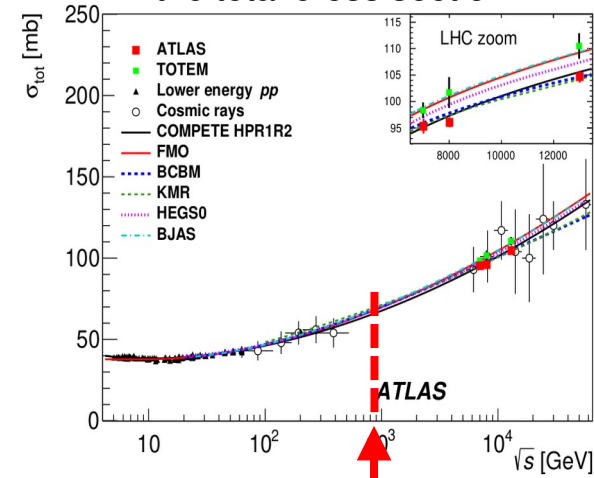
- $t \rightarrow 0$  requires SPECIAL RUNS:
  - 1) Special beam optics > giving the proton beams a very small angular spread
  - 2) Special detectors > Far away from the IP but very close to the proton beams

- ATLAS uses the method for a precise luminosity measurement to obtain the absolute normalization
- Differential elastic cross section:

$$\frac{d\sigma}{dt_i} = \frac{1}{\Delta t_i} \times \frac{\mathcal{M}^{-1} [N_i - B_i]}{A_i \times \epsilon^{reco} \times \epsilon^{trig} \times \epsilon^{DAQ} \times L_{int}}$$

One of main uncertainties

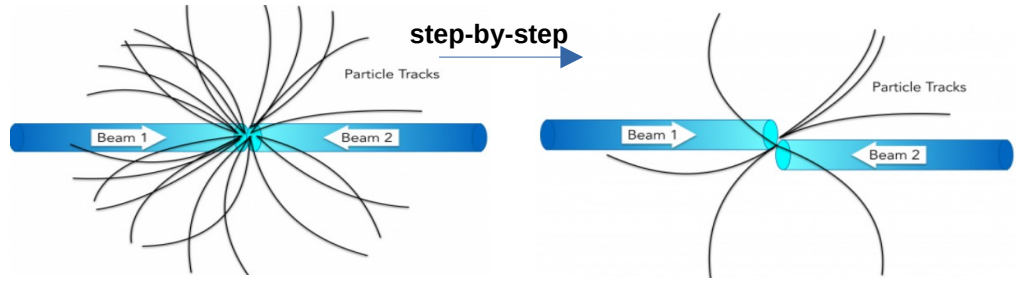
Energy evolution of the total cross section



$\sqrt{s} = 900$  GeV 2018 data-set:

- Luminosity calibration data taken in two different sessions: in October and in November
- Higher bunch intensities then usually
- Larger transverse beam sizes then usually
- 150 colliding bunch-pairs
- 2 unpaired bunches per beam

- The absolute luminosity scale can be determined from dedicated beam-separation scans (Van Der Meer scans)



- Luminosity can be expressed using beam parameters:

$$\mathcal{L}_b = \frac{f_r n_1 n_2}{2\pi \Sigma_x \Sigma_y}$$

$f_r n_1 n_2$  bunch current product  
 $2\pi \Sigma_x \Sigma_y$  convolved beam-sizes (computed from overlap integrals)

$$\Sigma_x = \frac{1}{\sqrt{2\pi}} \frac{\int R(\Delta x) d(\Delta x)}{R(\Delta x^{max})}$$

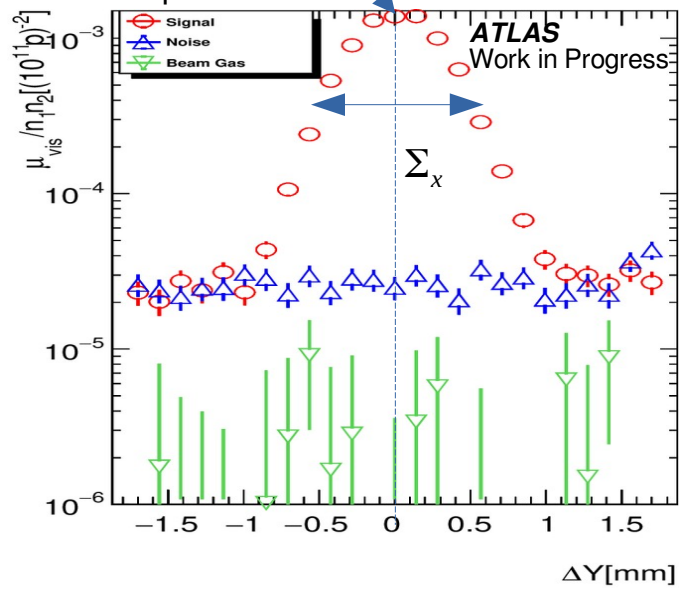
It is assumed that particle density functions (in each bunch) **can be factorized** into independent x and y components  
 → non-factorization correction

- Measuring interaction rate as  $\rightarrow \Sigma_x, \Sigma_y$  as a function of beam separation

- Visible cross-section is a **calibration constant**:

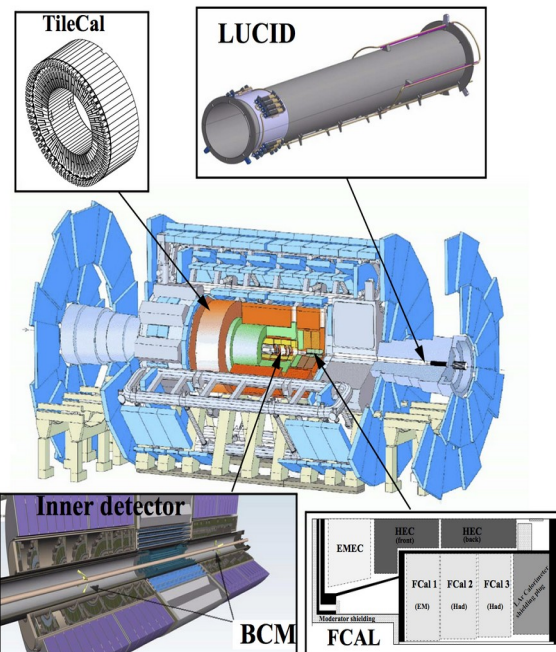
$$\sigma_{vis} = \mu_{vis}^{max} \frac{2\pi \Sigma_x \Sigma_y}{n_1 n_2}$$

Interaction rate at zero nominal separation



## Luminosity detectors:

- ▶ RUN-2 primary detectors:
  - **LUCID\* Čerenkov detector**
    - >Far forward region
    - >Provides bunch-by-bunch measurements
    - >Contains 16 photomultiplier tubes (PMTs)
    - >PMTs coated with radioactive  $^{207}\text{Bi} \rightarrow$  calibration signal
  - **BCM\*\* diamond detector**
    - >Provides bunch-by-bunch measurements
    - >1.84 m from the beam pipe
- ▶ Calorimeters:
  - **EMEC, FCal, TileCal**
    - >Measure bunch-integrated luminosity
- ▶ Track counting detectors
  - **Pixel and SCT detectors**



## Algorithms:

- ▶ Fundamental assumptions:
  - 1) The distribution of pp interactions is a Poisson distribution
  - 2) The efficiency to detect a single pp interaction is independent of a total number of interactions

▶ **EventOR-** Signal on A OR C side of the IP

▶ **HitOR-** Sum of recorded signals in all available detector modules  $N_{modules}$ :

$$\mu_{vis}^{HIT} = -\ln \left( 1 - \frac{N_{HIT}}{N_{BC} N_{Modules}} \right)$$

- Advantage: Large number of modules

▶ **EventAND-** Recorded signal on both sides of the IP

\*LUCID: LUMinosity Čerenkov Integrating Detector

\*\*BCM: Beam Condition Monitor

$$\sigma_{vis} = \mu_{vis}^{max} \frac{2\pi \Sigma_x \Sigma_y}{n_1 n_2}$$

- Devices for measuring bunch currents:
  - FBCT\*, BPTX\*
  - > sensitive to bunch structure
  - > have non-linear behavior
  - Offset correction
  - DCCT\*
  - > more accurate
  - > measures only bunch integrated current

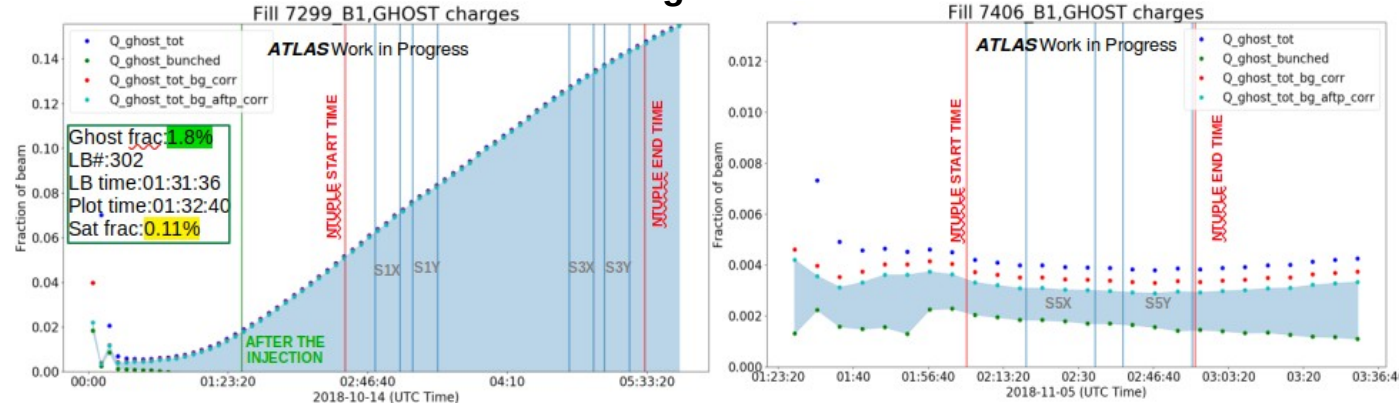
## Ghost charge and satellites bunches:

- Ghost charge → protons present in nominally empty bunch slots picked up by the more sensitive DCCT
- Satellites → protons present in the collision bunch slots measured by the FBCT in nominally empty RF buckets (10 RF buckets per 25 ns bunch slot)
- Bunch currents must be corrected for ghost charge and satellites as part of bunch integrated normalization

Aug 29, 2022

DCCT – DC Current Transformers \*  
 FBCT – Fast Beam-Current Transformers  
 BPTX – Beam-Pickup Timing system

## Ghost-charge time evolution



## Ghost-charge and satellites fraction of beam

Scan	Ghost[%]		Satellites[%]	
	B1	B2	B1	B2
1	7.5	7.0	0.35	0.36
3	13.5	13.0	0.6	0.6
4	7.5	8.0	0.3	0.4
5	0.3	0.25	0.05	0.05
6	0.3	0.26	0.05	0.05

Effect on  $\sigma_{vis}$

16%  
 34%  
 19%  
 0.6%  
 0.6%

October session  
 Extremely large level of ghost charge bias the determination of the visible cross-section

Typically level of ghost charge: Uncertainty estimated using only scans 5 and 6

November session

November session vdM scans were performed with better LHC RF system settings  
 → Therefore much worse ghost charge for scans 1, 3, 4

## Noise background

- Dominant source
- For LUCID algorithms is signal from Bismuth calibration source
- Estimated from the bunch-slot preceding colliding bunch-pair

$$\mu_{\text{vis, spec}}^i = \frac{\mu_{\text{vis}}^i}{n_1 n_2} - \frac{\mu_{\text{vis}}^{i-1}}{n_1 n_2} - \frac{n_1 \cdot \mu_{\text{vis, B1}}^{\text{beam-gas}} + n_2 \cdot \mu_{\text{vis, B2}}^{\text{beam-gas}}}{n_1 n_2}$$

Fills 7299-7300

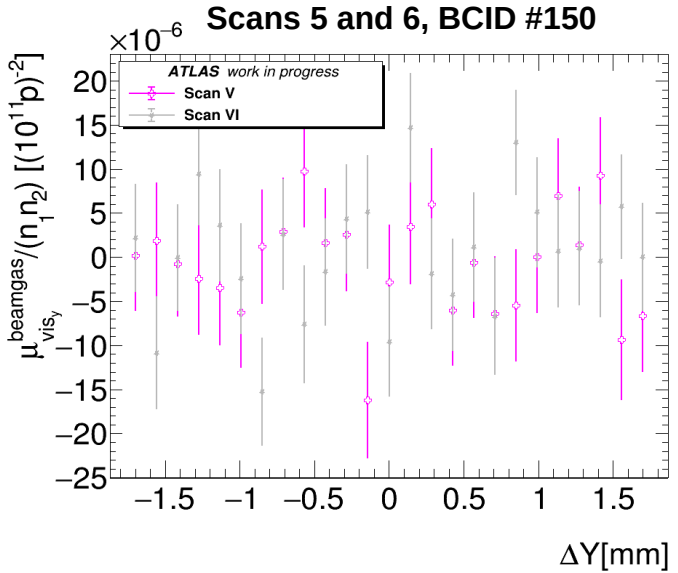
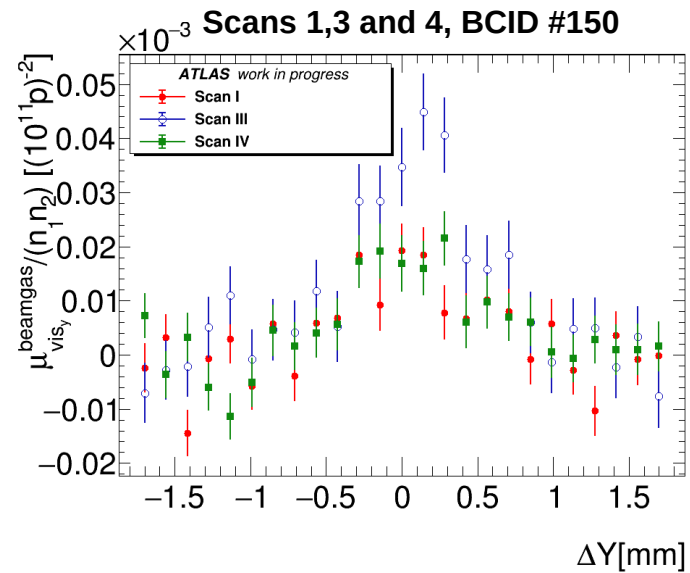
## Beam-gas background

- Subdominant effect
- Calculated using unpaired bunches:

$$\mu_{\text{vis, Bk}}^{\text{beam-gas}} = \frac{1}{N_{\text{unpaired}}} \sum_{i \in \text{unpaired}} \left( \frac{\mu_{\text{vis}}^i - \mu_{\text{vis}}^{i-1}}{n_{i,k}} \right)$$

- Scaled with bunch currents in colliding bunch-pairs

Estimated beam-gas background for a given colliding bunch



- The largest peak is consistent with the largest ghost-charge contamination for scan 3 (plot left)
- Scans 5 and 6 are only used for estimating background uncertainty (plot right)

- Parameters are determined empirically from the fit of Gaussian-like functions after subtracting background

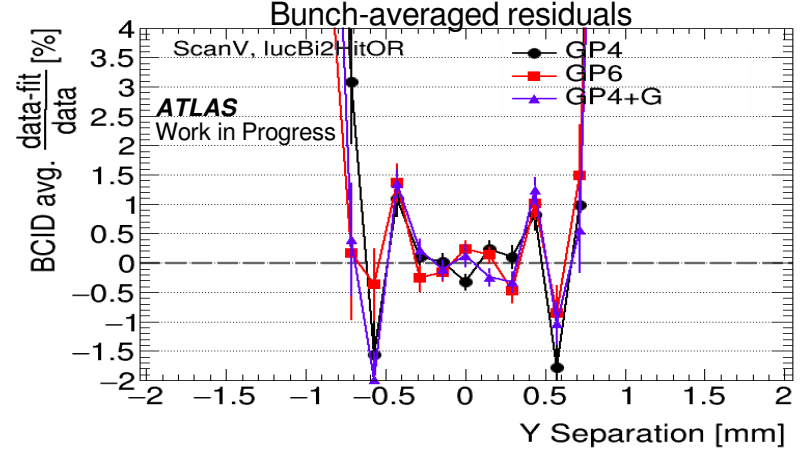
- Single Gaussian example:

$$\mathcal{R}(\Delta x) = \frac{A}{\sqrt{2\pi}\sigma} \exp\left(-\frac{\Delta x^2}{2\sigma^2}\right) \longrightarrow \Sigma_x = \frac{1}{\sqrt{2\pi}} \cdot \frac{\int_{-\infty}^{\infty} \mathcal{R}(\Delta x) d(\Delta x)}{\mathcal{R}(0)} = \sigma$$

Convolved beam size equals Gaussian width

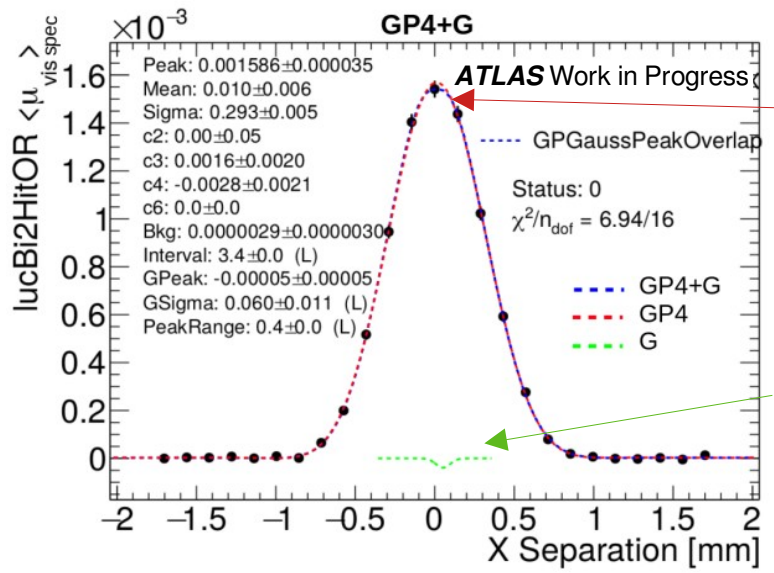
- Choice fit models:

- Best chi2/ndof
- Best residuals (especially at the peak)



- Default fit function for 900 GeV was 'GP4+G':
  - Linear combination of Gaussian multiplied by a 4<sup>th</sup> order polynomial and a single Gaussian
  - Single Gaussian for fitting the bulk of the distribution in order to ensure unbiased estimates of  $\mu_{vis}^{max}$

- 'GP4+G' fitting example



'GP4' overestimates peak

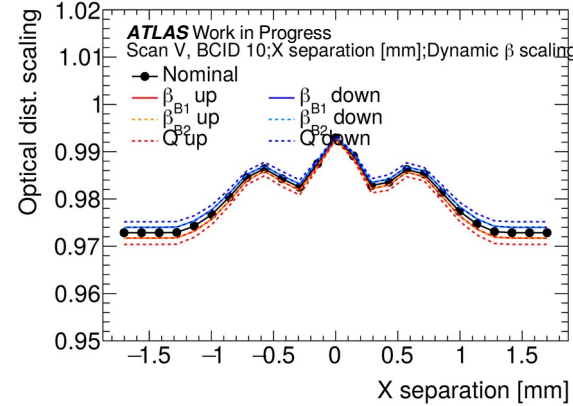
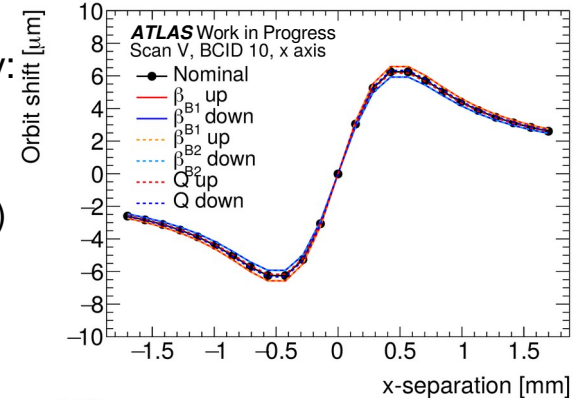
Additional -Gaussian used for fitting central five points



- **Beam-beam effects:**  
LHC beams interact electromagnetically:
  - 1) Mutual deflection of the two beams (computed using analytical equation)
  - 2) Defocussing leading to optical distortion (computed from simulations)

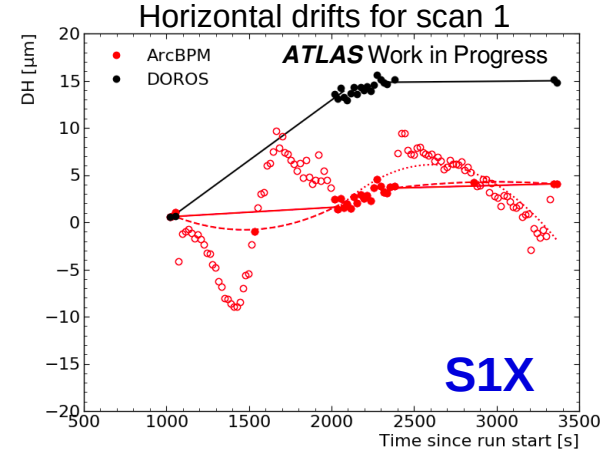
- **Beam-beam effects parameters:**
  - Beam-beam separation
  - Beam energy and transverse sizes of the beams
  - Bunch currents
  - Beta\* values
  - Fractional tune

- **Beam-beam deflection :**  
-Orbit shift is computed using the Bassetti-Erskine formula
- **Optical distortion:**  
- Based on simulations  
- Parametrization:  $\xi$ ,  $Q_x$ ,  $Q_y$
- **Systematic effects are calculated by** varying initial parameters within their errors



- **Size of beam-beam effects:**  
Beam-beam deflection (2.42- 3.11%) compensated by the  
Optical distortion (-1.84 - -2.31%)  
➤ Total beam-beam correction ~ 0.6%

- **Orbit-drift:**  
Drifts of the beam orbit affect the vdM calibration
  - 1) In-plane drift distort the scan curve and affect  $\Sigma$
  - 2) Drifts between scan peaks reduce peak luminosity and lower visible cross-section
  - 3) Out-of-plane drifts lead to lower  $\Sigma$



- **Devices for measuring beam positions:**  
-DOROS (Diode Orbit and Oscillation System)  
-arcBPM (BPMs located in the LHC arcs)
- **Size of corrections:** 0.03 - 0.12%
- **Uncertainty estimation:** Visible cross-section fractional difference between DOROS and arcBPM readings

Source of uncertainty	Uncertainty [%]
FBCT offset correction	0.02%
Orbit-drift correction	0.32%
Beam position jitter	0.14%
Emittance growth	0.34%
Bunch-by-bunch consistency	0.00%
Fit model	0.36%
Background subtraction	0.49%
Beam-beam effects	0.43%
Reference specific luminosity	0.56%
Ghost-charge and satellites subtraction	0.14%
Magnetic non-reproducibility and LSC	0.05%
Scan-to-Scan reproducibility	0.84%
<b>Total uncertainty</b>	<b>1.35%</b>

**Beam-conditions dependent uncertainties**

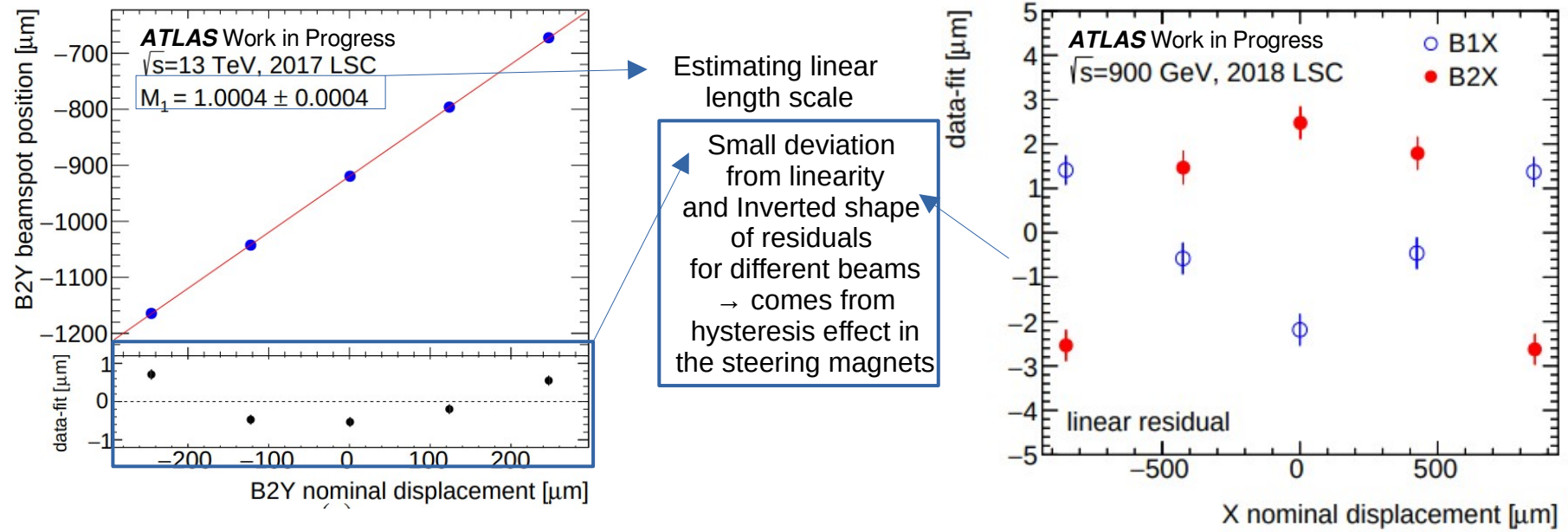
**Instrumental uncertainties**

- Uncertainties in table left uncorrelated between each other
- Dominant sources of uncertainty:
  - > Scan-to-scan reproducibility
  - > Reference specific luminosity
  - > Background subtraction
  - > Beam-beam effects
- Non-factorization uncertainty not included in the table left (uncertainty yet to be assessed)
- Total precision achieved ~ **1.35%**

- Luminosity is an important parameter of accelerator
- L systematics dominate several key SM measurements, like W, Z top cross sections as well as total pp cross section
- Calibration of the measured luminosity is done by analysing data from beam separation scans (van der Meer scans)
- The absolute precision lies in 1-2% range for pp
- In this talk we present vdM analysis of a special dataset at  $\sqrt{s}=900$  GeV
- Main contribution to the systematic uncertainties arise from Scan-to-Scan reproducibility, reference specific luminosity and background subtraction
- Overall uncertainty is 1.35% with non-factorization uncertainty yet to be assessed



- Nominal beam displacement so far = Intended beam separation using LHC steering magnets
- $\Sigma_x, \Sigma_y$  measurements requires knowledge of the ACTUAL beam displacement
- Length scale calibration scans are used for this purposes:
  - Target beam was moved to five equally-spaced positions
  - Target beam position measured using BEAMSPOT position
  - BEAMSPOT position: Position fitted from primary vertices reconstructed in the ID for head-on collision
  - HEAD-ON collision satisfied using miniscans of the non-target beam



➤ Estimated combined uncertainty for 900 GeV centre-of-mass energy ~0.05%

- Formalism based on the following assumption:

$$\mathcal{L}(\delta_x, \delta_y) = f_x(\delta_x) f_y(\delta_y)$$

- Evidence for non-factorization effect:

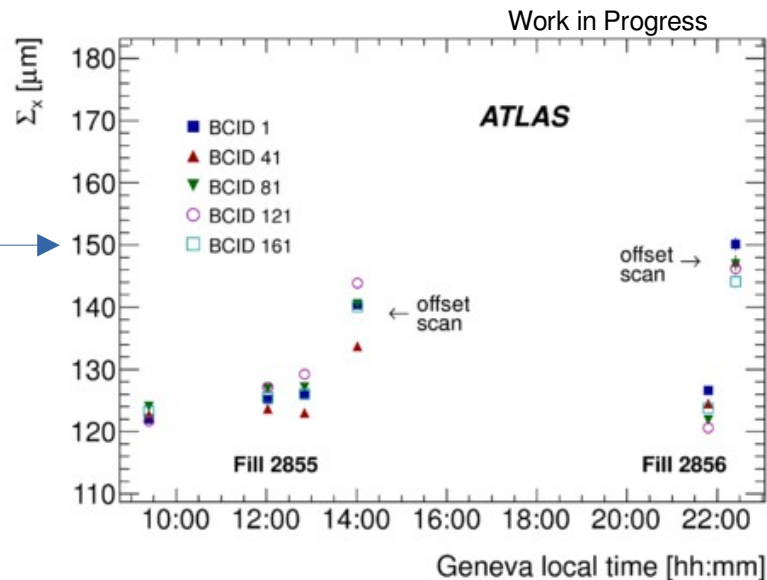
- $\Sigma_x, \Sigma_y$  are larger in offset scans

- Single beam parametrization for Non-Factorization effect:

- Fitting Luminosity vs. Beam separation → True luminosity unbiased by non-factorization effects
- Fitting Beamspot displacement vs. Beam separation
- Fitting Beamspot width vs. Beam separation

- Impact of non-factorization correction → Scan-to-scan reproducibility improvement

- 900 GeV 2018 data-set → Non-factorization effect uncertainty yet to be assessed (with maximal value of Run-2 pp 13 TeV vdM ~0.6%)

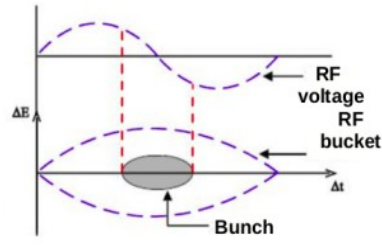


$$\sigma_{vis} = \mu_{vis}^{max} \frac{2\pi \Sigma_x \Sigma_y}{n_1 n_2}$$

- Devices for measuring bunch currents:
  - FBCT\*, BPTX\*
    - >sensitive to bunch structure
    - >have non-linear behavior
  - DCCT\*
    - >more accurate
    - >measures only bunch integrated current

## Ghost charge and satellites

- Ghost charge → protons that are present in nominally empty bunch slots that will still be picked up by the more sensitive DCCT
- Satellites → protons present in the collision bunch slots that are measured by the FBCT in nominally empty RF buckets (10 RF buckets per 25 ns bunch slot)



## Bunch-current normalization:

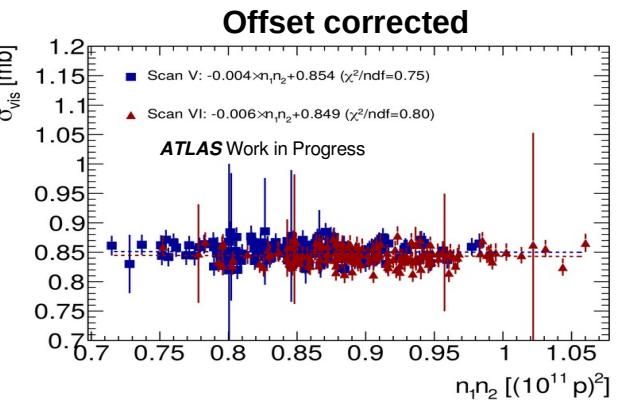
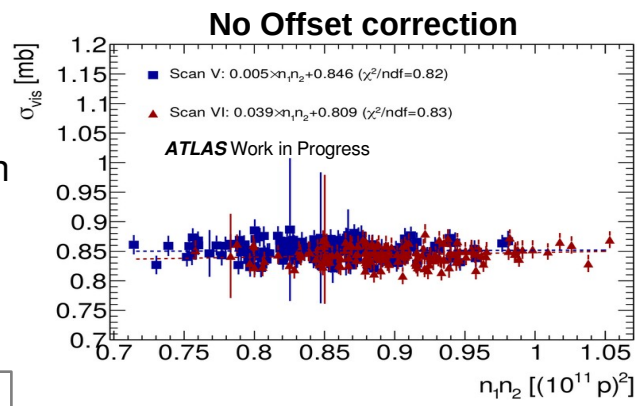
$$FBCT_{ikc} = GS \times \frac{DCCT_i}{FBCT_{iR}} \times FBCT_{ikR}$$

- 1) Bunch integrated measurement normalization to more accurate DCCT measurements
- 2) Determination of bunch-by-bunch fraction: FBCT & BPTX offset fits
- 3) Ghost-charge and satellites correction

## Offset correction

- Non-linear behaviour of bunch-currents is corrected by minimizing:

$$\chi^2(\bar{\sigma}_{vis}, b_1, b_2) = \sum_{i \in BCIDs} \left( \frac{S(\bar{\sigma}_{vis}, b_1, b_2, n_1^i, n_2^i) - \sigma_{vis}^{no\ off.,i}}{\Delta\sigma_{vis}^{no\ off.,i}} \right)^2$$



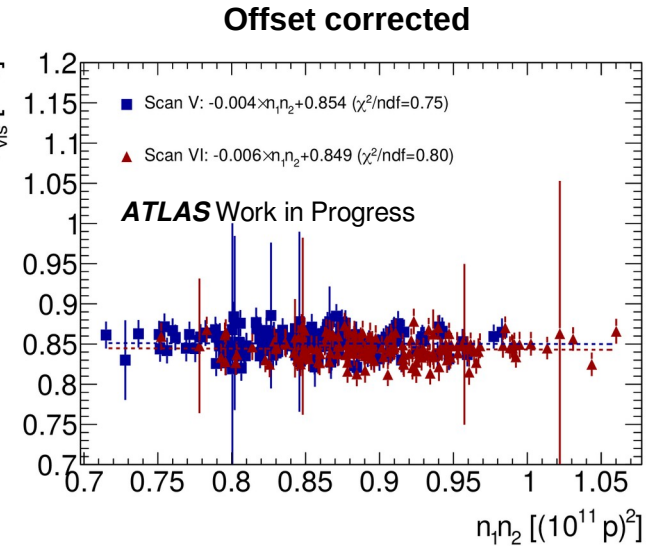
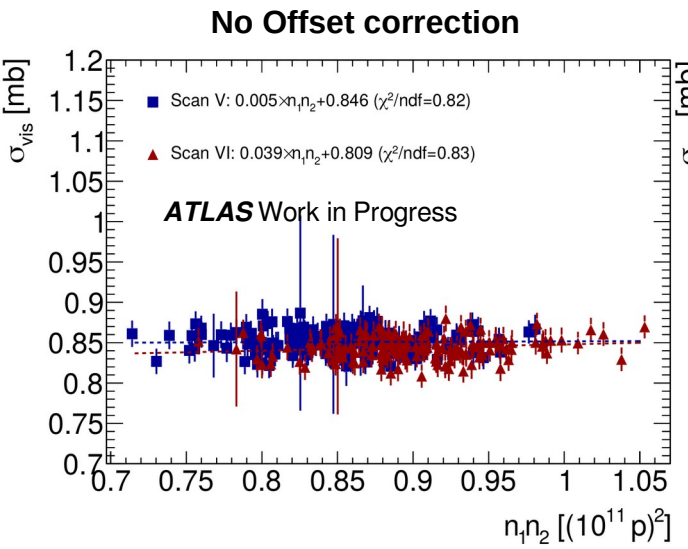
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DCCT – DC Current Transformers \*  
 FBCT – Fast Beam-Current Transformers  
 BPTX – Beam-Pickup Timing system

➤ Non-linear behaviour of bunch-currents is corrected by minimizing:

$$\chi^2(\bar{\sigma}_{\text{vis}}, b_1, b_2) = \sum_{i \in \text{BCIDs}} \left( \frac{S(\bar{\sigma}_{\text{vis}}, b_1, b_2, n_1^i, n_2^i) - \sigma_{\text{vis}}^{\text{no offs.}, i}}{\Delta \sigma_{\text{vis}}^{\text{no offs.}, i}} \right)^2, \text{ with}$$

$$S(\bar{\sigma}_{\text{vis}}, b_1, b_2, n_1^i, n_2^i) = \bar{\sigma}_{\text{vis}} \frac{n_1^i + b_1 \cdot (n_1^i - \bar{n}_1)}{n_1^i} \frac{n_2^i + b_2 \cdot (n_2^i - \bar{n}_2)}{n_2^i}.$$



### Calculated per-beam offsets

Scan	B1	B2
I	-0.06 ± 0.04	-0.019 ± 0.034
III	-0.019 ± 0.034	-0.01 ± 0.05
IV	0.04 ± 0.04	-0.06 ± 0.04
V	-0.03 ± 0.05	0.04 ± 0.05
VI	0.03 ± 0.05	0.05 ± 0.05

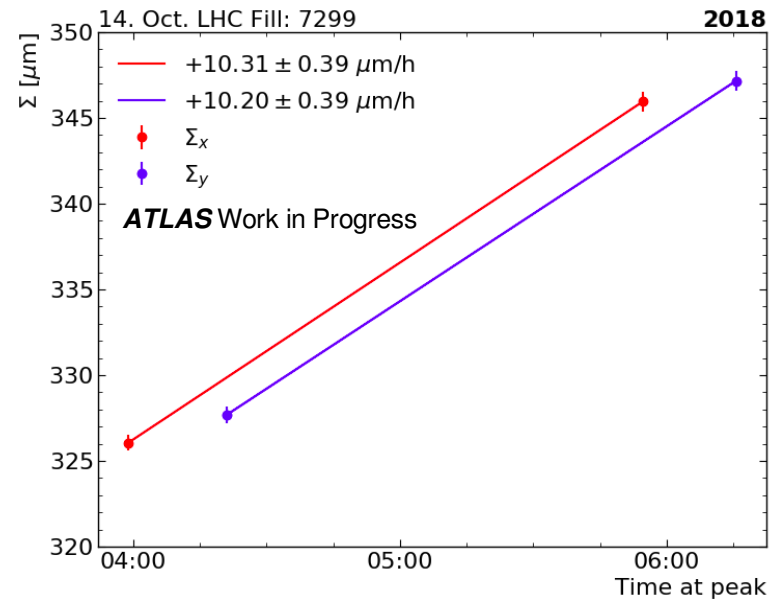
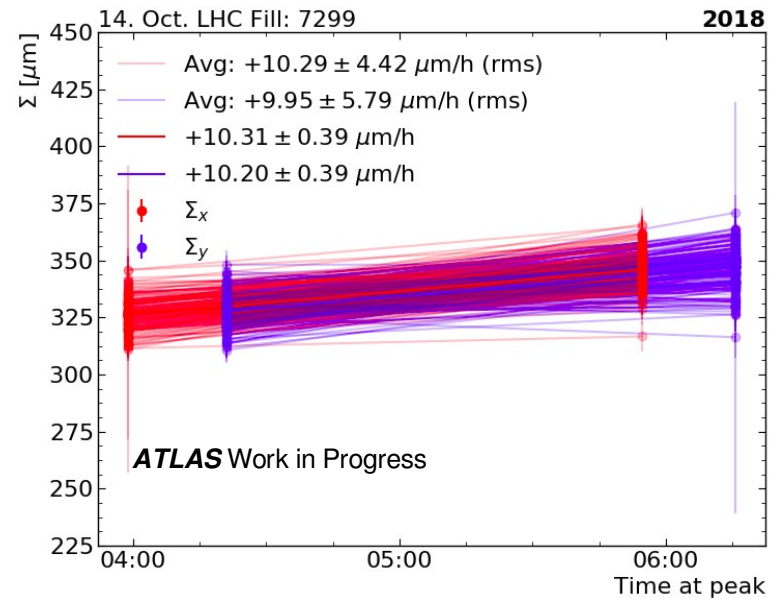
- For the final systematic uncertainty November session is used
- Syst. unc. is estimated as the largest difference between fBCT and BPTX SigVis (Nov session only used)

Scan #	Visible cross-section [mb]		SigVis Fractional difference [%]	
	No OFF corr.	fBCT OFF corr.	No/fBCT OFF corr.	FBCT/BPTX {OFF corr.}
I	0.887597	0.88302	0.52%	/
III	0.913962	0.910215	0.41%	/
IV	0.886374	0.885146	0.14%	/
V	0.85081	0.850686	0.01%	0.023%
VI	0.84413	0.843731	0.05%	0.013%



- Convolved beam sizes measured during a small period of time
- Emittance grow or shrink affecting calibration:
  - 1) Scan curves can be distorted by change of beam width
  - 2) Horizontal and vertical widths are measured at different periods of time → bias on  $\sigma_{vis}$

- Change of  $\Sigma$  is shown for Fill 7299
- Fill 7299 →  $\Sigma$  increasing both for x-scan and y-scan
- Fills 7300, 7406, 7407 → **less than two** on-axis scan available for estimating emittance growth
- Less transparent lines show the BbyB  $\Sigma$  change
- Slope of average ~ Average of slopes



Fill #	On-axis scans
7299	S1, S3
7300	S4
7406	S5
7407	S6

➤ Using following equation of SigVis for estimating corrections:

$$\sigma_{\text{vis}}(t_x, t_y) = 2\pi \times \frac{1}{2} (\mu_{\text{vis.}}^{\text{max}}(t_x) + \mu_{\text{vis.}}^{\text{max}}(t_y)) \times \Sigma_x(t_x)\Sigma_y(t_y)$$

➤ Expected Peak rates are estimated with assumption that SigVis is constant with time  $d\sigma_{\text{vis}}/dt = 0$  which yields:

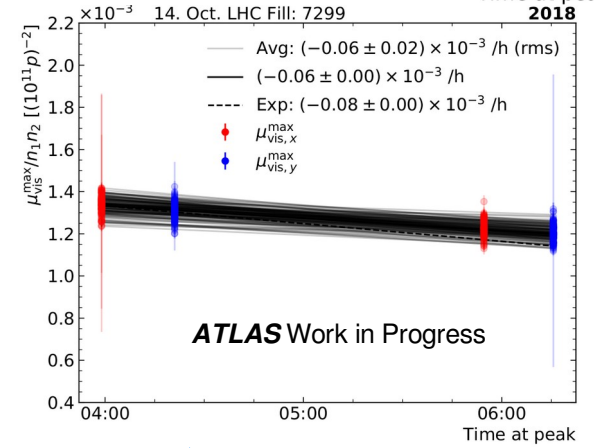
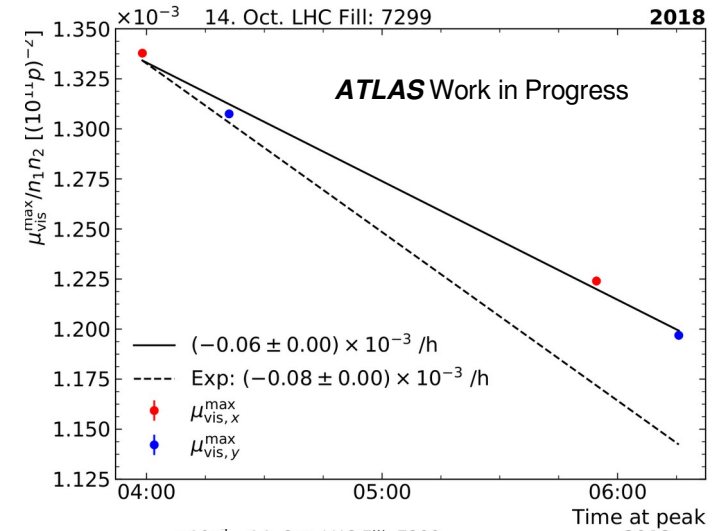
$$\frac{d\mu_{\text{vis.}}^{\text{max}}}{\mu_{\text{vis.}}^{\text{max}} dt} = - \left( \frac{d\Sigma_x}{\Sigma_x dt} + \frac{d\Sigma_y}{\Sigma_y dt} \right)$$

➤ Correction is:  $c_\epsilon = \sigma_{\text{vis}}(t_{\text{mid}}, t_{\text{mid}}) / \sigma_{\text{vis}}(\hat{t}_x, \hat{t}_y)$

time between peaks      at the peak times

$$\frac{1}{2} \left| \frac{\sigma_{\text{vis}}(\hat{t}_x) - \sigma_{\text{vis}}(\hat{t}_y)}{\sigma_{\text{vis,ref}}} \right|$$

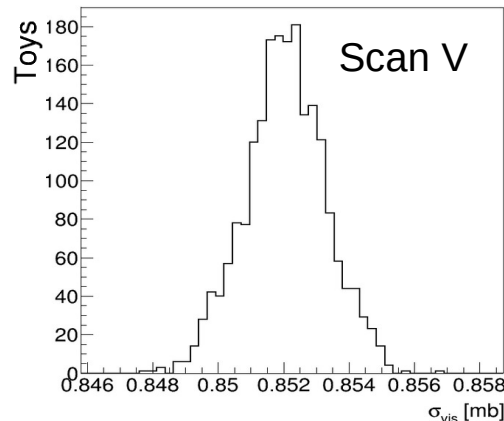
S#	Uncor. SigVis	Corr. SigVis	c [%]	delta c (x/y)	delta c (fit)
I	0.8897	0.8898	0.006	0.338	0.032
III	0.9148	0.9149	0.005	0.185	0.027



- Performing pseudo-experiment randomly changing samples:

$$x_{new} = x + rnd.Gauss(0, \sigma_{jitter})$$

- Using 2000 iterations (toys)
- Using RelRMS = RMS/SigVis to estimate uncertainty ~ 0.14%



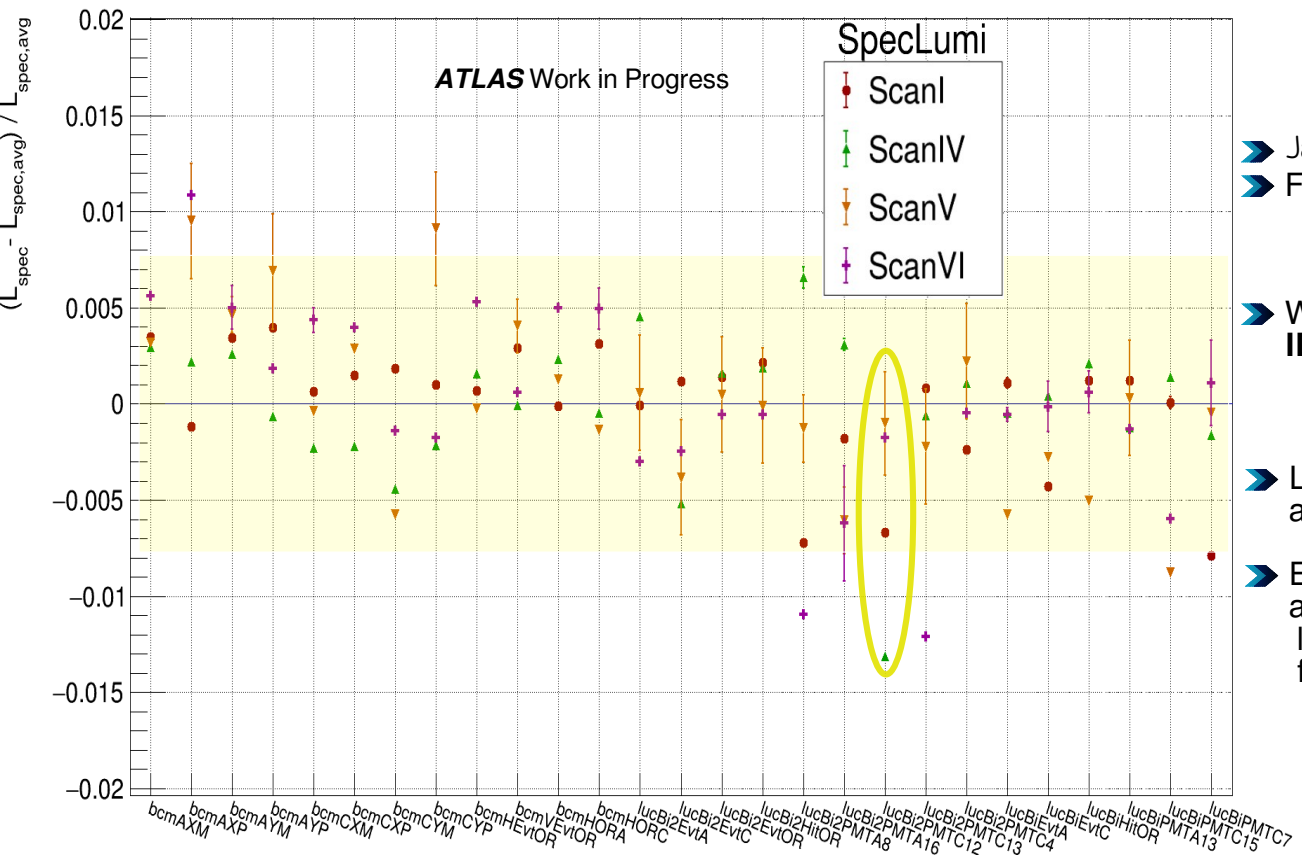
Scan	SigVis	RMS	RelRMS
I	0.879024	0.000894	0.10%
III	0.908484	0.000863	0.09%
IV	0.880739	0.000957	0.11%
V	0.852059	0.001227	<b>0.14%</b>
VI	0.849463	0.001034	0.12%

Scan	B-by-B
I	0
III	0.49%
IV	0
V	0
VI	0

- Bunch-by-bunch uncertainty is calculated RMS corrected for average  $\sigma_{vis}$  stat. unc:

$$RMS_{corr} = \frac{1}{\sigma_{vis}} \sqrt{RMS^2 - (\delta\sigma_{vis})^2}$$

- Bunch-by-bunch consistency is zero if RMS is smaller than  $\delta\sigma_{vis}$



- Jan's method has been used (explained here in detail):
- For each algorithm  $a$ , we use relative difference  $\Delta^a(s, b)$ 

$$\Delta^a(s, b) = \frac{L_{spec}^a(s, b) - \langle L_{spec}(s, b) \rangle}{\langle L_{spec}(s, b) \rangle}$$
- Where  $s$  and  $b$  are **scan numbers** and **colliding bunch IDs** respectively
- Largest uncertainty due to **mbts\*** algorithms and scan III.
- Excluding mbts\* algorithms and scan III from averaging we get **~0.56%** of uncertainty with largest scan averaged deviation coming from lucBi2PMTA12 algorithm.